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 Signals, Systems and Computers, 1993. 1993 Conference Record of The Twenty-Seventh Asilomar Conference on, 1-3 Nov 1993
 Page(s): 1514 -1518 vol.2

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2 **Maximum entropy method for estimating seismic wave amplitude**

Addeeb, A.; Omar, A.; Slivinsky, C.;
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3 **Stacking of noisy seismic traces via maximum entropy with a correlation coefficient constraint**

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6 High resolution velocity/depth spectra estimation for seismic profiling

Baggeroer, A.;

OCEANS , Volume: 6 , Aug 1974

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